256-Kbit (32K x 8) nvSRAM with Real-Time-Clock

Features

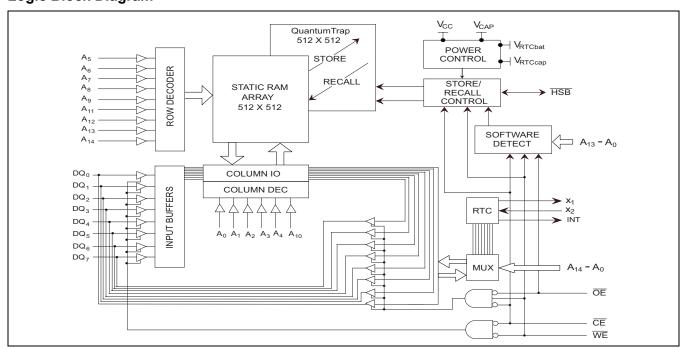
- Data integrity of Cypress nvSRAM combined with full featured real time clock
 - Low power, 300 nA Max, RTC current
 - Capacitor or battery backup for RTC
- · Watchdog timer
- · Clock alarm with programmable interrupts
- 25 ns, 35 ns, and 45 ns access times
- "Hands-off" automatic STORE on power down with only a small capacitor
- STORE to QuantumTrap™ initiated by software, device pin, or on power down
- · RECALL to SRAM initiated by software or on power up
- Infinite READ, WRITE, and RECALL cycles
- · High reliability
 - Endurance to 200K cycles
 - Data retention: 20 years @ 55°C
- 10 mA typical I_{CC} at 200 ns cycle time
- Single 3V operation with tolerance of +15%, -10%
- · Commercial and industrial temperature
- · SSOP Package (ROHS compliant)

Functional Description

The Cypress CY14B256K combines a 256 Kbit nonvolatile static RAM with a full featured real-time-clock in a monolithic integrated circuit. The embedded nonvolatile elements incorporate QuantumTrap technology producing the world's most reliable nonvolatile memory. The SRAM can be read and written an infinite number of times, while independent, nonvolatile data resides in the nonvolatile elements.

The real-time-clock function provides an accurate clock with leap year tracking and a programmable, high accuracy oscillator. The alarm function is programmable for one time alarms or periodic seconds, minutes, hours, or days. There is also a programmable watchdog timer for process control.

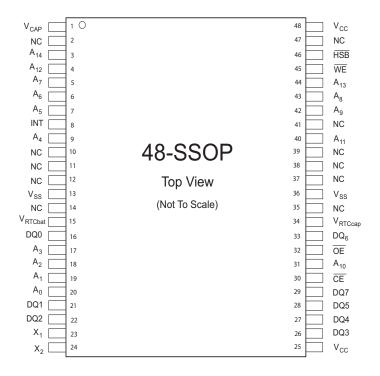
Logic Block Diagram



Cypress Semiconductor CorporationDocument Number: 001-06431 Rev. *E



Pin Configurations



Pin Definitions

Pin Name	IO Type	Description
A ₀ -A ₁₄	Input	Address Inputs used to select one of the 32,768 bytes of the nvSRAM.
DQ0-DQ7	Input/Output	Bidirectional Data IO lines. Used as input or output lines depending on operation.
NC	No Connect	No Connects. This pin is not connected to the die.
WE	Input	Write Enable Input, active LOW. When selected \underline{LOW} , enables data on the IO pins to be written to the address location latched by the falling edge of \overline{CE} .
CE	Input	Chip Enable Input, active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
ŌĒ	Input	Output Enable, active LOW. The active LOW OE input enables the data output buffers during read cycles. Deasserting OE high causes the IO pins to tri-state.
X ₁	Output	Crystal Connection, drives crystal on start-up.
X ₂	Input	Crystal Connection for 32.768-kHz crystal.
V _{RTCcap}	Power Supply	Capacitor-supplied backup RTC supply voltage. (Left unconnected if V _{RTCbat} is used)
V _{RTCbat}	Power Supply	Battery-supplied backup RTC supply voltage. (Left unconnected if V _{RTCcap} is used)
INT	Output	Interrupt Output . Can be programmed to respond to the clock alarm, the watchdog timer, and the power monitor. Programmable to either active HIGH (push/pull) or LOW (open-drain).
V _{SS}	Ground	Ground for the device. Must be connected to ground of the system.
V _{CC}	Power Supply	Power Supply inputs to the device.
HSB	Input/Output	Hardware Store Busy . When low this output indicates a Hardware Store is in progress. When pulled low external to the chip it will initiate a nonvolatile STORE operation. A weak internal pull-up resistor keeps this pin high if not connected. (Connection Optional)
V _{CAP}	Power Supply	AutoStore™ Capacitor . Supplies power to nvSRAM during power loss to store data from SRAM to nonvolatile elements.



Device Operation

The CY14B256K nvSRAM consists of two functional components paired in the same physical cell. The components are SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Data in the SRAM can be transferred to the nonvolatile cell (the STORE operation), or from the nonvolatile cell to SRAM (the RECALL operation). This architecture allows all cells to be stored and recalled in parallel. During the STORE and RECALL operations SRAM READ and WRITE operations are inhibited. The CY14B256K supports infinite reads and writes just like a typical SRAM. In addition, it provides infinite RECALL operations from the nonvolatile cells and up to 200,000 STORE operations.

SRAM Read

The CY14B256K performs a READ cycle whenever $\overline{\text{CE}}$ and $\overline{\text{OE}}$ are low while WE and HSB are high. The address specified on pins A₀₋₁₄ determines which of the 32,752 data bytes shall be accessed. When the READ is initiated by an address transition, the outputs will be valid after a delay of t_{AA} (READ cycle #1). If the READ is initiated by $\overline{\text{CE}}$ or $\overline{\text{OE}}$, the outputs will be valid at t_{ACE} or at t_{DOE} , whichever is later (READ cycle #2). The data outputs will repeatedly respond to address changes within the t_{AA} access time without the need for transitions on any control input pins, and will remain valid until another address change or until $\overline{\text{CE}}$ or $\overline{\text{OE}}$ is brought high, or $\overline{\text{WE}}$ or HSB is brought low.

SRAM Write

A WRITE cycle is performed whenever $\overline{\text{CE}}$ and $\overline{\text{WE}}$ are low and HSB is high. The address inputs must be stable prior to entering the WRITE cycle and must remain stable until either $\overline{\text{CE}}$ or $\overline{\text{WE}}$ goes high at the end of the cycle. The data on the common IO pins DQ $_{0-7}$ be written into the memory if the data is valid t_{SD} before the end of a $\overline{\text{WE}}$ controlled WRITE or before the end of an $\overline{\text{CE}}$ controlled WRITE. $\overline{\text{OE}}$ must be kept high during the entire WRITE cycle to avoid data bus contention on common IO lines. If $\overline{\text{OE}}$ is left $\underline{\text{low}}$, internal circuitry will turn off the output buffers t_{HZWE} after $\overline{\text{WE}}$ goes low.

AutoStore Operation

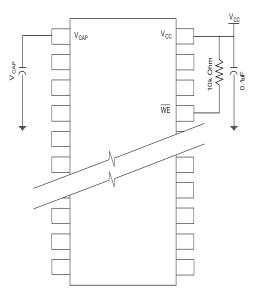
The CY14B256K stores data to nvSRAM using one of three storage operations. The three storage operations are Hardware Store - activated by HSB, Software Store - activated by an address sequence, and AutoStore - on device power down. AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B256K.

During normal operation, the device will draw current from V_{CC} to charge a capacitor connected to the V_{CAP} pin. This stored charge will be used by the chip to perform a single STORE operation. If the voltage on the V_{CC} pin drops below V_{SWITCH} , the part will automatically disconnect the V_{CAP} pin from V_{CC} . A STORE operation will be initiated with power provided by the V_{CAP} capacitor.

Figure 1 shows the proper connection of the storage capacitor. V_{CAP} for automatic store operation. Refer to the DC Electrical Characteristics on page 13 for the size of V_{CAP} . The voltage on the V_{CAP} pin is driven to 5V by a charge pump internal to

the chip. A pull up must be placed on $\overline{\text{WE}}$ to hold it inactive during power up.

Figure 1. AutoStore™ Mode



To reduce unnecessary nonvolatile stores, AutoStore and Hardware Store operations will be ignored unless at least one WRITE operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a WRITE operation has taken place. The HSB signal can be monitored by the system to detect an AutoStore cycle is in progress.

Hardware STORE (HSB) Operation

The CY14B256K provides the $\overline{\text{HSB}}$ pin for controlling and acknowledging the STORE operations. The $\overline{\text{HSB}}$ pin can be used to request a hardware STORE cycle. When the $\overline{\text{HSB}}$ pin is driven low, the CY14B256K will conditionally initiate a STORE operation after t_{DELAY}. An actual STORE cycle will only begin if a WRITE to the SRAM took place since the last STORE or RECALL cycle. The $\overline{\text{HSB}}$ pin also acts as an open drain driver that is internally driven low to indicate a busy condition while the STORE (initiated by any means) is in progress.

SRAM_READ and WRITE operations that are in progress when HSB is driven low by any means are given time to complete before the STORE operation is initiated. After HSB goes low, the CY14B256K will continue SRAM operations for t_{DELAY} . During t_{DELAY} , multiple SRAM READ operations may take place. If a WRITE is in progress when HSB is pulled low it will be allowed a time, t_{DELAY} , to complete. However, any SRAM WRITE cycles requested after HSB goes low will be inhibited until HSB returns high.

During any STORE operation, regardless of how it was initiated, the CY14B256K will continue to drive the HSB pin low, releasing it only when the STORE is complete. Upon completion of the STORE operation the CY14B256K will remain disabled until the HSB pin returns high.

If HSB is not used, it must be left unconnected.



Hardware RECALL (Power Up)

During power up, or after any low power condition ($V_{CC} < V_{SWITCH}$), an internal RECALL request will be latched. When V_{CC} once again exceeds the sense voltage of V_{SWITCH} , a RECALL cycle will be automatically initiated and will take $t_{HRECALL}$ to complete.

Software STORE

Data can be transferred from the SRAM to the nonvolatile memory by a software address sequence. The CY14B256K software STORE cycle is initiated by executing sequential CE controlled READ cycles from six specific address locations in exact order. During the STORE cycle an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. Once a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of READs from specific addresses is used for STORE initiation, it is important that no other READ or WRITE accesses intervene in the sequence, or the sequence will be aborted and no STORE or RECALL will take place.

To initiate the software STORE cycle, the following READ sequence must be performed:

- 1. Read address 0x0E38, Valid READ
- 2. Read address 0x31C7, Valid READ
- 3. Read address 0x03E0, Valid READ
- 4. Read address 0x3C1F, Valid READ
- 5. Read address 0x303F, Valid READ
- 6. Read address 0x0FC0, Initiate STORE cycle

The software sequence may be clocked with CE controlled READs or OE controlled READs. Once the sixth address in the sequence has been entered, the STORE cycle will commence and the chip will be disabled. It is important that READ cycles

and not WRITE cycles be used in the sequence. It is not necessary that OE be low for the sequence to be valid. After the t_{STORE} cycle time has been fulfilled, the SRAM will again be activated for READ and WRITE operation.

Software RECALL

Data can be transferred from the nonvolatile memory to the SRAM by a software address sequence. A software RECALL cycle is initiated with a sequence of READ operations in a manner similar to the software STORE initiation. To initiate the RECALL cycle, the following sequence of $\overline{\text{CE}}$ controlled READ operations must be performed:

- Read address 0x0E38, Valid READ
- 2. Read address 0x31C7, Valid READ
- 3. Read address 0x03E0, Valid READ
- 4. Read address 0x3C1F, Valid READ
- 5. Read address 0x303F, Valid READ
- 6. Read address 0x0C63, Initiate RECALL cycle

Internally, RECALL is a two step procedure. First, the SRAM data is cleared, and second, the nonvolatile information is transferred into the SRAM cells. After the t_{RECALL} cycle time the SRAM will once again be ready for READ and WRITE operations. The RECALL operation in no way alters the data in the nonvolatile elements.

Data Protection

The CY14B256K protects data from corruption during low voltage conditions by inhibiting all externally initiated STORE and WRITE operations. The low voltage condition is detected when $V_{CC} < V_{SWITCH}$. If the CY14B256K is in a WRITE mode (both CE and WE low) at power up, after a RECALL, or after a STORE, the WRITE will be inhibited until a negative transition on CE or WE is detected. This protects against inadvertent writes during power up or brown out conditions.

Table 1. Mode Selection

CE	WE	OE	A13-A0	Mode	Ю	Power
Н	X	Х	X	Not Selected	Output High Z	Standby
L	Н	L	X	Read SRAM	Output Data	Active
L	L	Х	Х	Write SRAM	Input Data	Active
L	Н	L	0x0E38 0x31C7 0x03E0 0x3C1F 0x303F 0x0FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Store	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active I _{CC2} [1, 2, 3]
L	Н	L	0x0E38 0x31C7 0x03E0 0x3C1F 0x303F 0x0C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Recall	Output Data Output Data Output Data Output Data Output Data Output Data Output High Z	Active [1, 2, 3]

Notes

Document Number: 001-06431 Rev. *E Page 4 of 23

^{1.} The six consecutive address locations must be in the order listed. WE must be HIGH during all six cycles to enable a nonvolatile cycle.

^{2.} While there are 15 address lines on the CY14B256K, only the lower 14 lines are used to control software modes.

^{3.} IO state depends on the state of \overline{OE} . The IO table shown is based on \overline{OE} Low.



Noise Considerations

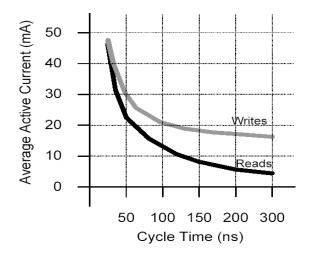
The CY14B256K is a high-speed memory and so must have a high-frequency bypass capacitor of approximately 0.1 μF connected between V_{CC} and V_{SS} , using leads and traces that are as short as possible. As with all high speed CMOS ICs, careful routing of power, ground, and signals will reduce circuit noise.

Low Average Active Power

CMOS technology provides CY14B256K which allows drawing less current when it is cycled at times longer than 50 ns. Figure 2 shows the relationship between I_{CC} and READ and/or WRITE cycle time. Worst case current consumption is shown for commercial temperature range, V_{CC} = 3.45V, and chip enable at maximum frequency. Only standby current is drawn when the chip is disabled. The overall average current drawn by the CY14B256K depends on the following items:

- 1. 1The duty cycle of chip enable.
- 2. The overall cycle rate for accesses.
- 3. The ratio of READs to WRITEs.
- 4. The operating temperature.
- 5. The V_{CC} level.
- 6. IO loading.

Figure 2. Current vs. Cycle Time



Real-Time-Clock Operation

nvTIME Operation

The CY14B256K consists of internal registers that contain clock, alarm, watchdog, interrupt, and control functions. Internal double buffering of the clock and the clock/timer information registers prevents accessing transitional internal clock data during a read or write operation. Double buffering also circumvents disrupting normal timing counts or clock accuracy of the internal clock while accessing clock data. Clock and Alarm Registers store data in BCD format.

Clock Operations

The clock registers maintain time up to 9,999 years in one second increments. The user can set the time to any calendar time and the clock automatically keeps track of days of the week and month, leap years, and century transitions. There are eight registers dedicated to the clock functions that are used to set time with a write cycle and to read time during a read cycle. These registers contain the time of day in BCD format. Bits defined as 0 are currently not used and are reserved for future use by Cypress.

Reading the Clock

While the double buffered RTC register structure reduces the chance of reading incorrect data from the clock, you to halt internal updates to the CY14B256K clock registers before reading clock data to prevent the reading of data in transition. Stopping the internal register updates does not affect clock accuracy. The update process is stopped by writing a 1 to the read bit R (in the flags register at 0x7FF0), and will not restart until a 0 is written to the read bit. The RTC registers can then be read while the internal clock continues to run. Within 20 ms after a 0 is written to the read bit, all CY14B256K registers are simultaneously updated.

Setting the Clock

Setting the write bit W (in the flags register at 0x7FF0) to a 1 stops updates to the CY14B256K registers. The correct day, date, and time can then be written into the registers in 24 hour BCD format. The time written is referred to as the Base Time. This value is stored in nonvolatile registers and used in calculation of the current time. Resetting the write bit to 0 transfers those values to the actual clock counters, after which the clock resumes normal operation.

Backup Power

The RTC in the CY14B256K is used for permanently powered operation. Either the V_{RTCcap} or V_{RTCbat} pin is connected depending on whether a capacitor or battery is chosen for the application. When primary power, V_{CC} , fails and drops below V_{SWITCH} the device will switch to the backup power supply.

The clock oscillator uses very little current, which maximizes the backup time available from the backup source. Regardless of clock operation with the primary source removed, the data stored in nvSRAM is secure, having been stored in the nonvolatile elements as power was lost.

During backup operation the CY14B256K consumes a maximum of 300 nA at 2V. Capacitor or battery values must be chosen according to the application. Backup time values based on maximum current specs are shown in Table 2, RTC Backup Time. Nominal times are approximately 3 times longer.

Table 2. RTC Backup Time

Capacitor Value	Backup Time
0.1F	72 hours
0.47F	14 days
1.0F	30 days

Using a capacitor has the advantage of recharging the backup source each time the system is powered up. If a battery is used, a 3V lithium is recommended and the CY14B256K will



only source current from the battery when the primary power is removed. The battery will not, however, be recharged at any time by the CY14B256K. The battery capacity must be chosen for total anticipated cumulative down time required over the life of the system.

Stopping and Starting the Oscillator

The OSCEN bit in calibration register at 0x7FF8 controls the starting and stopping of the oscillator. This bit is nonvolatile and shipped to customers in the enabled (set to 0) state. To preserve battery life while system is in storage OSCEN must be set to a 1. This will turn off the oscillator circuit, extending the battery life. If the OSCEN bit goes from disabled to enabled, it will take approximately take 5 seconds (10 seconds max) for the oscillator to start.

The CY14B256K has the ability to detect oscillator failure. This is recorded in the OSCF (Oscillator Failed bit) of the flags register at address 0x7FF0. When the device is powered on (V_{CC} goes above V_{SWITCH}) the OSCEN bit is checked for enabled status. If the OSCEN bit is enabled and the oscillator is not active, the OSCF bit is set. The user must check for this condition and then write a 0 to clear the flag. It must be noted that in addition to setting the OSCF flag bit, the time registers are reset to the Base Time (see the section Setting the Clock on page 5), which is the value last written to the timekeeping registers. The Control/Calibration register and the OSCEN bit are not affected by the oscillator failed condition.

If the voltage on the backup supply (either V_{RTCcap} or V_{RTCbat}) falls below its minimum level, the oscillator may fail, leading to the oscillator failed condition, which can be detected when system power is restored.

The value of OSCF must be reset to 0 when the time registers are written for the first time. This will initialize the state of this bit, which may have been set when the system was first powered on.

Calibrating the Clock

The RTC is driven by a quartz controlled oscillator with a nominal frequency of 32.768 kHz. Clock accuracy will depend on the quality of the crystal, usually specified to 35 ppm limits at 25°C. This error could equate to +1.53 minutes per month. The CY14B256K employs a calibration circuit that can improve the accuracy to +1/–2 ppm at 25°C. The calibration circuit adds or subtracts counts from the oscillator divider circuit.

The number of pulses that are suppressed (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five calibration bits found in calibration register at 0x7FF8. Adding counts speeds the clock up; subtracting counts slows the clock down. The calibration bits occupy the five lower order bits in the control register 8. These bits can be set to represent any value between 0 and 31 in binary form. Bit D5 is a sign bit, where a 1 indicates positive calibration and a 0 indicates negative calibration. Calibration occurs within a 64 minute cycle. The first 62 minutes in the cycle may, once per minute, have one second either shortened by 128 or lengthened by 256 oscillator cycles.

If a binary 1 is loaded into the register, only the first 2 minutes of the 64 minute cycle will be modified; if a binary 6 is loaded, the first 12 will be affected, and so on. Therefore each

calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125,829,120 actual oscillator cycles. That is 4.068 or –2.034 ppm of adjustment per calibration step in the calibration register.

In order to determine how to set the calibration one may set the CAL bit in the flags register at 0x7FF0 to 1, which causes the INT pin to toggle at a nominal 512 Hz. Any deviation measured from the 512 Hz will indicate the degree and direction of the required correction. For example, a reading of 512.010124 Hz would indicate a +20 ppm error, requiring a -10 (001010) to be loaded into the Calibration register. Note that setting or changing the calibration register does not affect the frequency test output frequency.

Alarm

The alarm function compares user programmed values to the corresponding time-of-day values. When a match occurs, the alarm event occurs. The alarm drives an internal flag, AF, and may drive the INT pin if desired.

There are four alarm match fields. They are date, hours, minutes, and seconds. Each of these fields also has a Match bit that is used to determine if the field is used in the alarm match logic. Setting the Match bit to 0 indicates that the corresponding field will be used in the match process.

Depending on the Match bits, the alarm can occur as specifically as one particular second on one day of the month, or as frequently as once per second continuously. The MSB of each alarm register is a Match bit. Selecting none of the Match bits (all 1s) indicates that no match is required. The alarm occurs every second. Setting the match select bit for seconds to 0 causes the logic to match the seconds alarm value to the current time of day. Since a match will occur for only one value per minute, the alarm occurs once per minute. Likewise, setting the seconds and minutes Match bits causes an exact match of these values. Thus, an alarm will occur once per hour. Setting seconds, minutes and hours causes a match once per day. Lastly, selecting all match values causes an exact time and date match. Selecting other bit combinations will not produce meaningful results; however the alarm circuit must follow the functions described.

There are two ways a user can detect an alarm event, by reading the AF flag or monitoring the INT pin. The AF flag in the flags register at 0x7FF0 will indicate that a date and time match has occurred. The AF bit will be set to 1 when a match occurs. Reading the Flags/Control register clears the alarm flag bit (and all others). A hardware interrupt pin may also be used to detect an alarm event.

Watchdog Timer

The watchdog timer is a free running down counter that uses the 32 Hz clock (31.25 ms) derived from the crystal oscillator. The oscillator must be running for the watchdog to function. It begins counting down from the value loaded in the Watchdog Timer register.

The counter consists of a loadable register and a free running counter. On power up, the watchdog time out value in register 0x7FF7 is loaded into the counter load register. Counting begins on power up and restarts from the loadable value any time the Watchdog Strobe (WDS) bit is set to 1. The counter is compared to the terminal value of 0. If the counter reaches this value, it causes an internal flag and an optional interrupt

Page 6 of 23

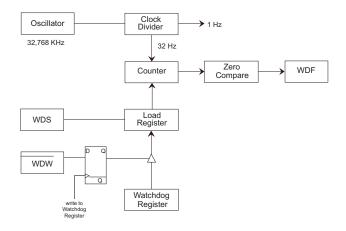


output. You can prevent the time out interrupt by setting WDS bit to 1 prior to the counter reaching 0. This causes the counter to be reloaded with the watchdog time out value and to be restarted. As long as the user sets the WDS bit prior to the counter reaching the terminal value, the interrupt and flag never occurs.

New time out values can be written by setting the watchdog write bit to 0. When the WDW is 0 (from the previous operation), new writes to the watchdog time out value bits D5-D0 allow the time out value to be modified. When WDW is a 1, writes to bits D5-D0 will be ignored. The WDW function allows a user to set the WDS bit without concern that the watchdog timer value will be modified. A logical diagram of the watchdog timer is shown in Figure 3. Note that setting the watchdog time out value to 0 would be otherwise meaningless and therefore disables the watchdog function.

The output of the watchdog timer is a flag bit WDF that is set if the watchdog is allowed to time out. The flag is set upon a watchdog time out and cleared when the Flags/Control register is read by the user. The user can also enable an optional interrupt source to drive the INT pin if the watchdog time out occurs.

Figure 3. Watchdog Timer Block Diagram



Power Monitor

The CY14B256K provides a power management scheme with power fail interrupt capability. It also controls the internal switch to backup power for the clock and protects the memory from low $V_{\rm CC}$ access. The power monitor is based on an internal band gap reference circuit that compares the $V_{\rm CC}$ voltage to various thresholds.

As described in the AutoStore Operation on page 3, when V_{SWITCH} is reached as V_{CC} decays from power loss, a data store operation is initiated from SRAM to the nonvolatile elements, securing the last SRAM data state. Power is also switched from VCC to the backup supply (battery or capacitor) to operate the RTC oscillator.

When operating from the backup source, no data may be read or written and the clock functions are not available to the user. The clock continues to operate in the background. Updated clock data is available to the user after VCC has been restored

to the device and tHRECALL delay (see AutoStore/Power Up RECALL on page 16).

Interrupts

The CY14B256K provides three potential interrupt sources. They include the watchdog timer, the power monitor, and the clock/calendar alarm. Each can be individually enabled and assigned to drive the INT pin. In addition, each has an associated flag bit that the host processor can use to determine the cause of the interrupt. Some of the sources have additional control bits that determine functional behavior. In addition, the pin driver has three bits that specify its behavior when an interrupt occurs.

The three interrupts each have a source and an enable. Both the source and the enable must be active (true high) in order to generate an interrupt output. Only one source is necessary to drive the pin. The user can identify the source by reading the Flags/Control register, which contains the flags associated with each source. All flags are cleared to 0 when the register is read. The flags will be cleared only after a complete read cycle (WE high); The power monitor has two programmable settings that are explained in the power monitor section.

Once an interrupt source is active, the pin driver determines the behavior of the output. It has two programmable settings as shown in the following sections. Pin driver control bits are located in the interrupts register.

According to the programming selections, the pin can be driven in the backup mode for an alarm interrupt. In addition, the pin can be an active LOW (open-drain) or an active HIGH (push-pull) driver. If programmed for operation during backup mode, it can only be active LOW. Lastly, the pin can provide a one shot function so that the active condition is a pulse or a level condition. In one shot mode, the pulse width is internally fixed at approximately 200 ms. This mode is intended to reset a host microcontroller. In level mode, the pin goes to its active polarity until the Flags/Control register is read by the user. This mode is intended to be used as an interrupt to a host microcontroller. The Interrupt register is initialized to 00h. The control bits are summarized as follows:

Watchdog Interrupt Enable - WIE. When set to 1, the watchdog timer drives the INT pin as well as an internal flag when a watchdog time out occurs. When WIE is set to 0, the watchdog timer affects only the internal flag.

Alarm Interrupt Enable - AIE. When set to 1, the alarm match drives the INT pin as well as an internal flag. When set to 0, the alarm match only affects to internal flag.

Power Fail Interrupt Enable - PFE. When set to 1, the power fail monitor drives the pin as well as an internal flag. When set to 0, the power fail monitor affects only the internal flag.

High/Low - H/L. When set to a 1, the INT pin is active HIGH and the driver mode is push pull. The INT pin can drive high only when $V_{CC} > V_{SWITCH}$. When set to a 0, the INT pin is active LOW and the drive mode is opendrain. Active LOW (open drain) is operational even in battery backup mode.

Pulse/Level - P/L. When set to a 1 and an interrupt occurs, the INT pin is driven for approximately 200 ms. When P/L is set to a 0, the INT pin is driven high or low (determined by H/L) until the Flags/Control register is read.

When an enabled interrupt source activates the INT pin, an external host can read the Flags/Control register to determine

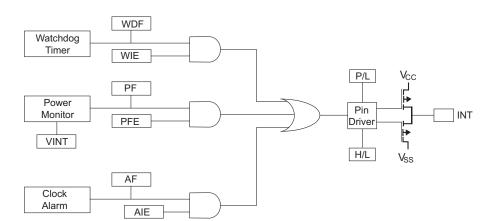


the cause. Remember that all flags will be cleared when the register is read. If the INT pin is programmed for Level mode, then the condition will clear and the INT pin will return to its inactive state. If the pin is programmed for Pulse mode, then reading the flag also will clear the flag and the pin. The pulse will not complete its specified duration if the Flags/Control register is read. If the INT pin is used as a host reset, then the Flags/Control register must not be read during a reset.

During a power on reset with no battery, the interrupt register is automatically loaded with the value 24h. This causes power fail interrupt to be enabled with an active low pulse.

Flags Register - The Flags register has three flag bits: WDF, AF, and PF. These flag bits are initialized to 00h. These flags are set by the watchdog time out, alarm match, or power fail monitor respectively. The processor can either poll this register or enable interrupts to be informed when a flag is set. The flags are automatically reset once the register is read.

Figure 4. RTC Recommended Component Configuration



WDF - Watchdog Timer Flag WIE - Watchdog Interrupt

PF - Power Fail Flag

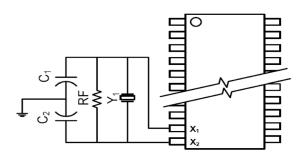
PFE - Power Fail Enable

AF - Alarm Flag

AIE - Alarm Interrupt Enable

P/L - Pulse Level

H/L - High/Low



Recommended Values

Y1 = 32.768KHz

RF = 10M Ohm

 $C_1 = 0$ $C_2 = 56 \text{ pF}$



Table 3. RTC Register Map

	BCD Format Data								
Register	D7	D6	D5	D4	D3	D2	D1	D0	Function/Range
0x7FFF		10s	Years			Y	ears		Years: 00-99
0x7FFE	0	0	0	10s Months		Mo	onths		Months: 01–12
0x7FFD	0	0	10s Day	of Month		Day 0	Of Month		Day of Month: 01–31
0x7FFC	0	0	0	0	0		Day of w	eek	Day of week: 01–07
0x7FFB	0	0	10s F	lours		Н	ours		Hours: 00-23
0x7FFA	0	1	0s Minute	s		Mi	nutes		Minutes: 00-59
0x7FF9		1	0s Second	ds		Se	conds		Seconds: 00-59
0x7FF8	OSCEN	0	Cal Sign			Calibrati	on		Calibration Values [4]
0x7FF7	WDS	WDW			V	VDT			Watchdog ^[4]
0x7FF6	WIE	AIE	PFE	0	H/L	P/L	0	0	Interrupts [4]
0x7FF5	M	0	10s Alar	m Date		Alar	m Day		Alarm, Day of Month: 01–31
0x7FF4	M	0	10s Aları	m Hours		Alarr	n Hours		Alarm, Hours: 00-23
0x7FF3	M	10 /	Alarm Min	utes	Alarm Minutes			Alarm, Minutes: 00-59	
0x7FF2	M	10 /	Alarm Min	utes	Alarm, Seconds			Alarm, Seconds: 00-59	
0x7FF1		10s C	enturies		Centuries			Centuries: 00–99	
0x7FF0	WDF	AF	PF	OSCF	0	CAL	W	R	Flags ^[4]

Table 4. Register Map Detail

	Time Keeping - Years								
	D7	D6	D5	D4	D3	D2	D1	D0	
	10s Years Years								
0x7FFF				ear. Lower nibbles from 0 to 9. T				e contains the	
				Time Keepin	g - Months				
	D7	D6	D5	D4	D3	D2	D1	D0	
	0	0	0	10s Month		Мс	onths		
0x7FFE				er nibble contain tes from 0 to 1.); upper nibble	
				Time Keepi	ng - Date				
	D7	D6	D5	D4	D3	D2	D1	D0	
	0	0	10s Day	of Month		Day o	f Month		
0x7FFD	upper nibble			month. Lower r perates from 0					
				Time Keep	ing - Day				
	D7	D6	D5	D4	D3	D2	D1	D0	
	0 0 0 0 Day of Week							(
0x7FFC				es to day of the gign meaning to					

Note:

Document Number: 001-06431 Rev. *E Page 9 of 23

^{4.} Is a binary value, not a BCD value.



Table 4. Register Map Detail (continued)

				Time Keepir	ng - Hours			
	D7	D6	D5	D4	D3	D2	D1	D0
	12/24	0	10s H	Hours		Н	ours	
0x7FFB				r format. Lower digit and operate				
				Time Keepin	g - Minutes			
	D7	D6	D5	D4	D3	D2	D1	D0
	0		10s Minutes			Mir	nutes	
0x7FFA				nibble contains tes from 0 to 5.				upper nibble
				Time Keeping	g - Seconds			
	D7	D6	D5	D4	D3	D2	D1	D0
	0		10s Seconds			Sec	conds	
0x7FF9				r nibble contains 0 to 5. The ran			es from 0 to 9;	upper nibble
				Calibration	/Control			
	D7	D6	D5	D4	D3	D2	D1	D0
0X7FF8	OSCEN	0	Calibration Sign			Calibration		
OSCEN				ator is halted. W ge. On a no-bat				g the oscillator
Calibration Sign	Determines i	f the calibration	n adjustment is	applied as an a	ddition to or a	s a subtraction	n from the time	e-base.
Calibration	These five bi	ts control the c	alibration of the	clock.				
				WatchDo	g Timer			
	D7	D6	D5	D4	D3	D2	D1	D0
0x7FF7	WDS	WDW			WE)T		
WDS				ds and restarts t log timer is rese				
WDW	Watchdog Write Enable. Setting this bit to 1 masks the watchdog time-out value (WDT5–WDT0) so it cannot be written. This allows the user to strobe the watchdog without disturbing the time-out value. Setting this bit to 0 allows bits 5–0 to be written on the next write to the Watchdog register. The new value will be loaded on the next internal watchdog clock after the write cycle is complete. This function is explained in more detail in the watchdog timer section.							
WDT	a multiplier of maximum time	f the 32-Hz cou ne-out is 2 seco	int (31.25 ms). Tonds (setting of	g timer interval i The minimum ra 3Fh). Setting th cleared to 0 on	nge or time-ou e watchdog til	ut value is 31.2 mer register to	25 ms (a settin	g of 1) and the



Table 4. Register Map Detail (continued)

				Interrupt Sta	tus/Control			
	D7	D6	D5	D4	D3	D2	D1	D0
0x7FF6	WIE	AIE	PFIE	0	H/L	P/L	0	0
WIE				and a watchdog e watchdog time				es the INT pin
AIE		pt Enable. Who		alarm match dri	ves the INT pi	n as well as th	e AF flag. Whe	en set to 0, the
PFIE			et to 1, the alar nly the PF flag.	m match drives	the INT pin a	s well as the F	PF flag. When	set to 0, the
H/L	High/Low. W	hen set to a 1,	the INT pin is d	riven active HIG	H. When set	to 0, the INT p	in is open drai	n, active LOW
P/L				driven active (de en to an active le				
				Alarm	- Day			
	D7	D6	D5	D4	D3	D2	D1	D0
	M	0	10s Ala	rm Date		Aları	m Date	
0x7FF5	Contains the	alarm value fo	r the date of the	e month and the	mask bit to s	select or desel	ect the date va	ılue.
M		ng this bit to 0 ca ore the date va		alue to be used	in the alarm n	natch. Setting	this bit to 1 cau	ses the match
				Alarm -	Hours			
	D7	D6	D5	D4	D3	D2	D1	D0
	M	0	10s Alar	m Hours		Alarn	n Hours	
0x7FF4	Contains the	alarm value fo	r the hours and	the mask bit to	select or des	elect the hour	s value.	
M		ng this bit to 0 of to ignore the h		s value to be us	sed in the alar	m match. Set	ting this bit to	causes the
				Alarm - N	/linutes			
	D7	D6	D5	D4	D3	D2	D1	D0
	M	0	10s Alarn	n Minutes		Alarm	Minutes	
0x7FF3	Contains the	alarm value fo	r the minutes a	nd the mask bit	to select or d	eselect the mi	inutes value.	
M		ng this bit to 0 co		ites value to be	used in the al	arm match. S	etting this bit to	1 causes the
				Alarm - S	econds			
	D7	D6	D5	D4	D3	D2	D1	D0
	M	0	10s Alarm	Seconds		Alarm	Seconds	
0x7FF2	Contains the	alarm value fo	r the seconds a	and the mask bi	t to select or o	leselect the se	econds' value.	
M			auses the seco seconds value.	nds' value to be	used in the a	larm match. S	etting this bit to	1 causes the
				Time Keeping	- Centuries			
	D7	D6	D5	D4	D3	D2	D1	D0



Table 4. Register Map Detail (continued)

		Flags									
	D7	D6	D5	D4	D3	D2	D1	D0			
0x7FF0	WDF	AF	PF	OSCF	0	CAL	W	R			
WDF				set to 1 when the Flags/Control			d to reach 0 w	vithout being			
AF				nen the time and lags/Control reg		ne values store	ed in the alarm	registers with			
PF			only bit is set to I register is read	1 when power fad.	alls below the	power-fail thre	eshold V _{SWITC}	CH. It is cleared			
OSCF	This indicate	s that time cou		nly if the oscilla er valid. The use ver cycles.							
CAL				square wave is o sabled) on powe		NT pin. When	set to 0, the IN	IT pin resumes			
W	Write Time. Setting the W bit to 1 freeze updates of the timekeeping registers. The user can then write them with updated values. Setting the W bit to 0 causes the contents of the time registers to be transferred to the timekeeping counters. The W-bit enables writes to RTC, Alarm, Calibration, Interrupt, and Flag registers.										
R	register. The	user can then r	ead them witho	static image of t ut concerns ove e, so the bit mus	r changing va	lues causing s	ystem errors.				



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. For user guidelines, not tested. Storage Temperature-65°C to +150°C Ambient Temperature with Power Applied –55°C to +125°C Supply Voltage on V_{CC} Relative to GND.........-0.5V to 4.1V Voltage Applied to Outputs in High-Z State-0.5V to V_{CC} + 0.5V Input Voltage –0.5V to Vcc+0.5V Transient Voltage (<20 ns) on Any Pin to Ground Potential.....–2.0V to V_{CC} + 2.0V

Package Power Dissipation Capability (T _A = 25°C)	1.0W
Surface Mount Pb Soldering Temperature (3 Seconds)	+260°C
Output Short Circuit Current [5]	15 mA
Static Discharge Voltage(per MIL-STD-883, Method 3015)	> 2001V
Latch-up Current	> 200 mA

Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0°C to +70°C	2.7V to 3.45V
Industrial	–40°C to +85°C	2.7V to 3.45V

DC Electrical Characteristics

Over the Operating Range (VCC = 2.7V to 3.45V) [6, 7, 8]

Parameter	Description	Test Conditions	Min	Max	Unit	
I _{CC1}	Average V _{CC} Current	t_{RC} = 35 ns t_{RC} = 45 ns	Commercial		65 55 50	mA mA mA
		Dependent on output loading and cycle rate. Values obtained without output loads. I _{OUT} = 0mA.	Industrial		55 (t _{RC} = 45 ns)	mA mA mA
I _{CC2}	Average V _{CC} Current during STORE	All Inputs Don't Care, V _{CC} = Max Average current for duration t _{STORE}			3	mA
I _{CC3}		WE > (V _{CC} – 0.2). All other inputs cycling. Dependent on output loading and cycle rate. Values obtained without output loads.			10	mA
I _{CC4}	Average V _{CAP} Current during AutoStore Cycle	All Inputs Don't Care, V _{CC} = Max Average current for duration t _{STORE}			3	mA
I _{SB}	V _{CC} Standby Current	$\overline{\rm WE}$ > (V _{CC} - 0.2). All others V _{IN} < 0.2V or > (V _{CC} standby current level after nonvolatile cycle is conjugate to the state of the state			3	mA
I _{IX}	Input Leakage Current	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}$		-1	+1	μА
I _{OZ}	Off-State Output Leakage Current	$V_{CC} = Max$, $V_{SS} \le V_{IN} \le V_{CC}$, CE or OE > V_{IH}		-1	+1	μА
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3	V
V _{IL}	Input LOW Voltage			V _{SS} - 0.5	0.8	V
V _{OH}	Output HIGH Voltage	I _{OUT} = –2 mA		2.4		V
V _{OL}	Output LOW Voltage	I _{OUT} = 4 mA			0.4	V
V _{CAP}	Storage Capacitor	Between V _{CAP} pin and V _{SS} , 5V Rated		17	120	μF

- 5. Outputs shorted for no more than one second. No more than one output shorted at a time.
- 6. Typical conditions for the Active Current shown on the front page of the data sheet are average values at 25°C (room temperature), and VCC = 3V. Not 100% tested. 7. The HSB pin has IOUT = -10μ A for VOH of 2.4 V, this parameter is characterized but not tested.
- 8. The INT pin is open-drain and does not source or sink current when Interrupt Register bit D3 is low.

Document Number: 001-06431 Rev. *E



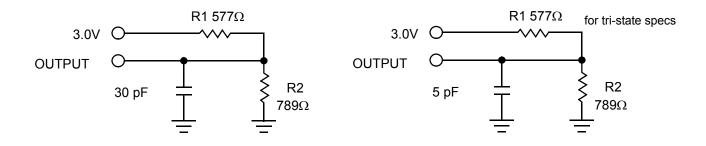
Capacitance [9]

Parameter	Description	Test Conditions	Max	Unit
C _{IN}	Input Capacitance	T _A = 25°C, f = 1 MHz,	7	pF
C _{OUT}	Output Capacitance	$V_{CC} = 0 \text{ to } 3.0 \text{ V}$	7	pF

Thermal Resistance [9]

Par	ameter	Description Test Conditions		48-SSOP	Unit
	U/A	(Junction to Ambient)	Test conditions follow standard test methods and procedures for measuring thermal impedance, in	TBD	°C/W
(30	Thermal Resistance (Junction to Case)	accordance with EIA / JESD51.	TBD	°C/W

AC Test Loads



AC Test Conditions

Input Pulse Levels0 V to	3 V
Input Rise and Fall Times (10% - 90%)	<u>≤</u> 5 ns
Input and Output Timing Reference Levels	1.5 V

Note:

Document Number: 001-06431 Rev. *E

These parameters are guaranteed but not tested.



AC Switching Characteristics

Parar	neter		25ns	part	35ns	part	45ns part		
Cypress Alt. Parameter Parameter		Description	Min Max		Min	Max	Min	Max	Unit
SRAM Read	Cycle								
t _{ACE}	t _{ACS}	Chip Enable Access Time		25		35		45	ns
t _{RC} ^[10]	t _{RC}	Read Cycle Time	25		35		45		ns
t _{AA} ^[11]	t _{AA}	Address Access Time		25		35		45	ns
t _{DOE}	t _{OE}	Output Enable to Data Valid		12		15		20	ns
t _{OHA} [11]	t _{OH}	Output Hold After Address Change	3		3		3		ns
t _{LZCE} [12]	t_{LZ}	Chip Enable to Output Active	3		3		3		ns
t _{HZCE} [12]	t_{HZ}	Chip Disable to Output Inactive		10		13		15	ns
t _{LZOE} [12]	t _{OLZ}	Output Enable to Output Active	0		0		0		ns
t _{HZOE} [12]	t _{OHZ}	Output Disable to Output Inactive		10		13		15	ns
t _{PU} ^[9]	t _{PA}	Chip Enable to Power Active	0		0		0		ns
t _{PD} ^[9]	t _{PS}	Chip Disable to Power Standby		25		35		45	ns
SRAM Write	Cycle				•	•		•	•
t _{WC}	t _{WC}	Write Cycle Time	25		35		45		ns
t _{PWE}	t _{WP}	Write Pulse Width	20		25		30		ns
t _{SCE}	t _{CW}	Chip Enable To End of Write	20		25		30		ns
t _{SD}	t _{DW}	Data Set-Up to End of Write	10		12		15		ns
t _{HD}	t _{DH}	Data Hold After End of Write	0		0		0		ns
t _{AW}	t _{AW}	Address Set-Up to End of Write	20		25		30		ns
t _{SA}	t _{AS}	Address Set-Up to Start of Write	0		0		0		ns
t _{HA}	t _{WR}	Address Hold After End of Write	0		0		0		ns
t _{HZWE} [12, 13]	t _{WZ}	Write Enable to Output Disable		10		13		15	ns
t _{LZWE} [12]	t _{OW}	Output Active after End of Write	3		3		3		ns

Notes:

10. WE must be HIGH during SRAM Read Cycles.

11. Device is continuously selected with CE and OE both Low.

12. Measured ±200 mV from steady state output voltage.

13. If WE is Low when CE goes Low, the outputs remain in the High Impedance State.



AutoStore/Power Up RECALL

		CY14	CY14B256K		
Parameter	Description	Min	Max	Unit	
t _{HRECALL} [14]	Power Up RECALL Duration		20	ms	
t _{STORE} [15, 16]	STORE Cycle Duration		12.5	ms	
V _{SWITCH}	Low Voltage Trigger Level		2.65	V	
t _{VCCRISE}	VCC Rise Time	150		μS	

Software Controlled STORE/RECALL Cycle [17, 18]

		25ns part		35ns	part	part 45ns		
Parameter	Description	Min	Max	Min	Max	Min	Max	Unit
t _{RC}	STORE/RECALL Initiation Cycle Time	25		35		45		ns
t _{AS}	Address Set-Up Time	0		0		0		ns
t _{CW}	Clock Pulse Width	20		25		30		ns
t _{GHAX}	Address Hold Time	1		1		1		ns
t _{RECALL}	RECALL Duration		100		100		100	μS
t _{SS} [19, 20]	Soft Sequence Processing Time		70		70		70	μS

Hardware STORE Cycle

		CY14E	3256K	
Parameter	Description	Min	Max	Unit
t _{DELAY} [21]	Time allowed to complete SRAM Cycle	1	70	μs
t _{HLHX}	Hardware STORE Pulse Width	15		ns

RTC Characteristics

Parameter	Description	Test Conditions		Min	Max	Unit
I _{BAK} ^[22]	RTC Backup Current		Commercial		300	nA
			Industrial		350	nA
V _{RTCbat} ^[23]	RTC Battery Pin Voltage		Commercial	1.8	3.3	V
			Industrial	1.8	3.3	V
V _{RTCcap} [24]	RTC Capacitor Pin Voltage		Commercial	1.2	2.7	V
			Industrial	1.2	2.7	V
tOCS		@Min. Temperature from Power up or Enable	Commercial		10	sec
	Start	@25°C Temperature from Power up or Enable	Commercial		5	sec
		@Min. Temperature from Power up or Enable	Industrial		10	sec
		@25°C Temperature from Power up or Enable	Industrial		5	sec

Notes:

- 14. t_{HRECALL} starts from the time V_{CC} rises above V_{SWITCH}.
 15. If an SRAM Write has not taken place since the last nonvolatile cycle, no STORE will take place.
 16. Industrial Grade Devices require 15 ms Max

- 17. The software sequence is clocked with $\overline{\text{CE}}$ -controlled or $\overline{\text{OE}}$ -controlled READs.
- 18. The six consecutive addresses must be read in the order listed in the Mode Selection table. WE must be HIGH during all six consecutive cycles.
- 19. This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register command.
- 20. Commands like STORE and RECALL lock out IO until operation is complete which further increases this time. See specific command.
- 21. Read and Write cycles in progress before HSB are given this amount of time to complete.
- 22. From either V_{RTCcap} or V_{RTCbat}.
 23. Typical = 3.0V during normal operation.
- 24. Typical = 2.4V during normal operation.

Document Number: 001-06431 Rev. *E Page 16 of 23



Switching Waveforms

Figure 5. SRAM Read Cycle #1: Address Controlled $^{[10,\ 11,\ 25]}$

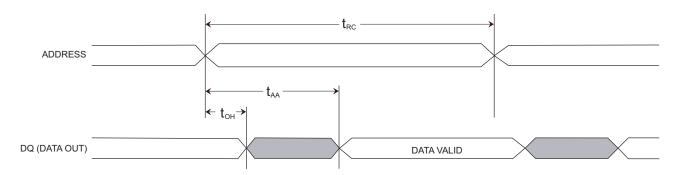
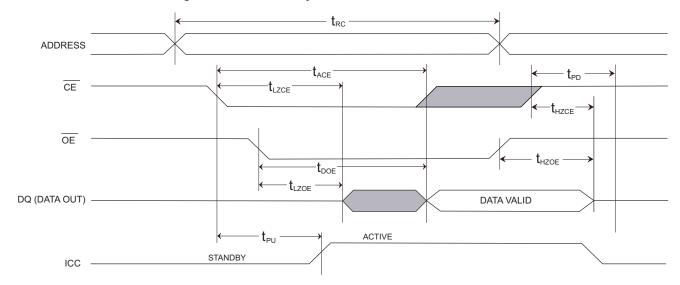


Figure 6. SRAM Read Cycle #2: $\overline{\text{CE}}$ and $\overline{\text{OE}}$ Controlled [10, 25]



Note:

25. HSB must remain HIGH during READ and WRITE cycles.



Switching Waveforms (continued)

Figure 7. SRAM Write Cycle #1: WE Controlled [25, 26]

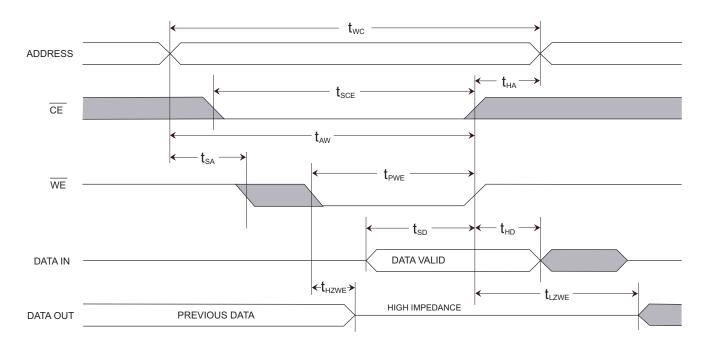
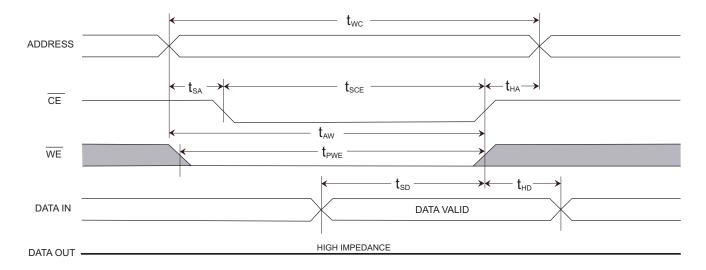


Figure 8. SRAM Write Cycle #2: CE Controlled



Note: 26. $\overline{\text{CE}}$ or $\overline{\text{WE}}$ must be > V_{IH} during address transitions.



Switching Waveforms (continued)

Figure 9. AutoStore/Power Up RECALL

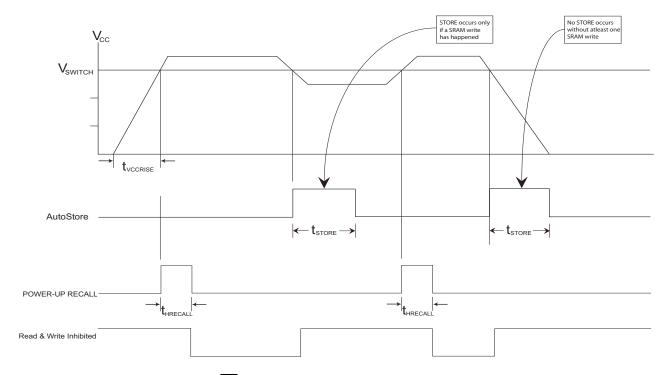
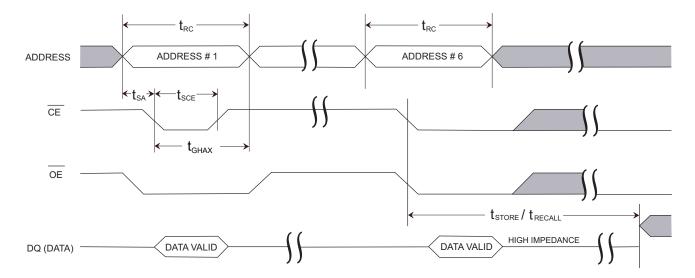


Figure 10. CE-controlled Software STORE/RECALL Cycle [18]





Switching Waveforms (continued)

Figure 11. OE-controlled Software STORE/RECALL Cycle [18]

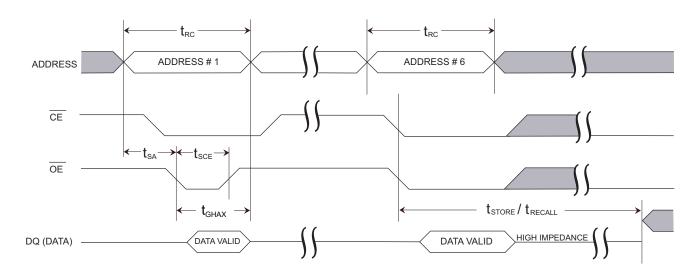


Figure 12. Soft Sequence Processing [19, 20]

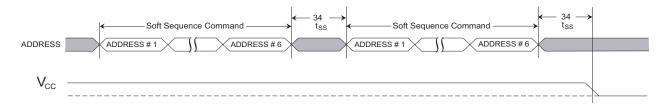
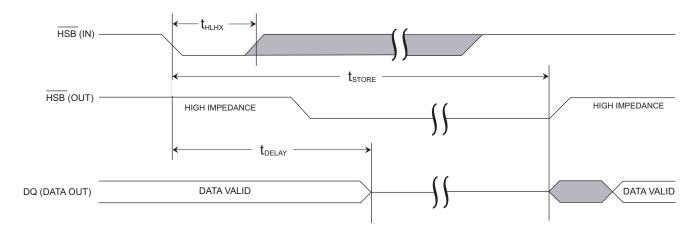
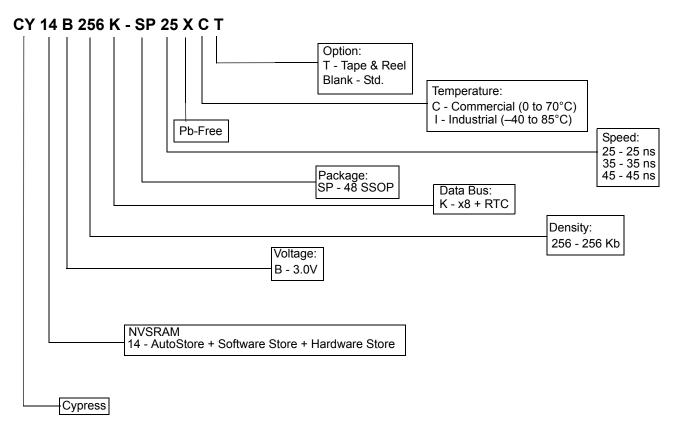


Figure 13. Hardware STORE Cycle





PART NUMBERING NOMENCLATURE



Ordering Information

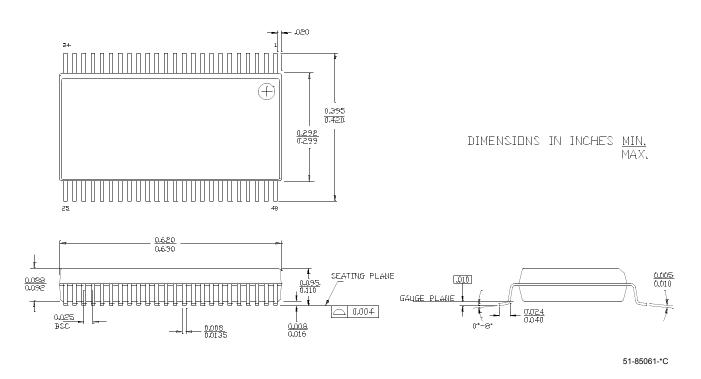
All of the above mentioned parts are of "Pb-free" type. Shaded areas contain advance information. Contact your local Cypress sales representative for availability of these parts.

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
25	CY14B256K-SP25XCT	51-85061	48-pin SSOP	Commercial
35	CY14B256K-SP35XCT	51-85061	48-pin SSOP	Commercial
45	CY14B256K-SP45XCT	51-85061	48-pin SSOP	Commercial
45	CY14B256K-SP45XIT	51-85061	48-pin SSOP	Industrial
	CY14B256K-SP45XI	51-85061	48-pin SSOP	



Package Diagrams

Figure 14. 48-pin Shrunk Small Outline Package, 51-85061



AutoStore and QuantumTrap are registered trademarks of Simtek Corporation. All products and company names mentioned in this document are the trademarks of their respective holders.



Document History Page

Document Title: CY14B256K, 256-Kbit (32K x 8) nvSRAM with Real-Time-Clock Document Number: 001-06431

Document	Number. 00	1-00-01		T
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	425138	See ECN	TUP	New Data Sheet
*A	437321	See ECN	TUP	Show Data Sheet on external Web
*B	471966	See ECN	TUP	Changed V _{IH(MIN)} from 2.2V to 2.0V Changed t _{RECALL} from 60µs to 100µs Changed Endurance from 1Million Cycles to 500K Cycles Changed Data Retention from 100 Years to 20 Years Added Soft Sequence Processing Time Waveform Updated Part Numbering Nomenclature and Ordering Information Added RTC Characteristics Table Added RTC Recommended Component Configuration
*C	503277	See ECN	PCI	Changed from "Advance" to "Preliminary" Changed the term "Unlimited" to "Infinite" Changed endurance from 500K cycles to 200K cycles Device operation: Tolerance limit changed from +20% to +15% in the "Features Section" and "Operating Range Table" Removed Icc1 values from the DC table for 25 ns and 35 ns industrial grade Changed V _{SWITCH(MIN)} from 2.55V to 2.45V Added temperature spec. to data retention - 20 years at 55°C Updated "Part Nomenclature Table" and "Ordering Information Table"
*D	597004	See ECN	TUP	Removed $V_{SWITCH(min)}$ spec from the AutoStore/Power Up RECALL table Changed t_{GLAX} spec from 20ns to 1ns Added $t_{DELAY(max)}$ spec of 70 μ s in the Hardware STORE Cycle table Removed t_{HLBL} specification Changed t_{SS} specification form 70 μ s(min) to 70 μ s(max) Changed $V_{CAP(max)}$ from 57 μ F to 120 μ F
*E	696097	See ECN	VKN	Added footnote #7 related to HSB Added footnote #8 related to INT pin Changed t _{GLAX} to t _{GHAX} Removed ABE bit from Interrupt register

[+] Feedback